## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10764454	SAITOH ET AL.
Examiner	Art Unit
Oueenie Debahan	1701

SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES				
Search Notes	Date	Examiner		
Search updated	6/12/08	QSD		

INTERFERENCE SEARCH				
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